MOSFET – Power, N-Channel, SUPERFET[®] III, Easy Drive

650 V, 12 A, 250 m Ω

FCPF250N65S3R0L-F154

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provides superior switching performance, and withstand extreme dv/dt rate. Consequently, SUPERFET III MOSFET Easy drive series helps manage EMI issues and allows for easier design implementation.

Features

- 700 V @ T_J= 150°C
- Typ. $R_{DS(on)} = 210 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 24 nC)
- Low Effective Output Capacitance (Typ. Coss(eff.) = 248 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

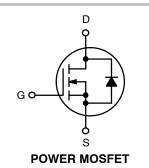
- Computing / Display Power Supplies
- Telecom / Server Power Supplies
- Industrial Power Supplies
- Lighting / Charger / Adapter

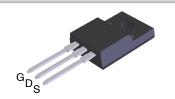


ON Semiconductor®

www.onsemi.com

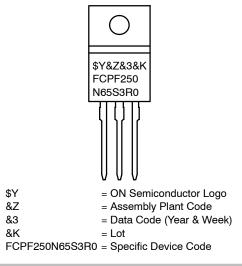
V _{DSS}	R _{DS(ON)} MAX	I _D MAX		
650 V	250 m Ω @ 10 V	12 A		





TO-220F Ultra Narrow Lead CASE 221BN

MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Parameter		Value	Unit
V _{DSS}	Drain to Source Voltage		650	V
V _{GSS}	Gate to Source Voltage	– DC	±30	V
		– AC (f > 1 Hz)	±30	
I _D	Drain Current	– Continuous (T _C = 25°C)	12*	А
		– Continuous (T _C = 100°C)	7.6*	
I _{DM}	Drain Current	– Pulsed (Note 1)	30*	А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		57	mJ
I _{AS}	Avalanche Current (Note 2)		2.3	А
E _{AR}	Repetitive Avalanche Energy (Note 1)		0.31	mJ
dv/dt MOSFET dv/dt			100	V/ns
	Peak Diode Recovery dv/dt (Note 3)		20	
P _D	Power Dissipation	(T _C = 25°C)	31	W
		- Derate Above 25°C	0.25	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
ΤL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality stresses exceeding those listed in the Maximum Hatings table may damage to should not be assumed, damage may occur and reliability may be affected. *Drain current limited by maximum junction temperature. 1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. $I_{AS} = 2.3 \text{ A}$, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}\text{C}$. 3. $I_{SD} \leq 6 \text{ A}$, di/dt $\leq 200 \text{ A}/\mu\text{s}$, $V_{DD} \leq 400 \text{ V}$, starting $T_J = 25^{\circ}\text{C}$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	4.07 °C/V	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Shipping
FCPF250N65S3R0L-154	FCPF250N65S3R0	TO-220F (Pb-Free)	50 Units / Tube

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS	•	-	-	•	
BV _{DSS}	Drain to Source Breakdown Voltage	V_{GS} = 0 V, I_D = 1 mA, T_J = 25°C	650	-	-	V
		V_{GS} = 0 V, I _D = 1 mA, T _J = 150°C	700	-	-	V
$\Delta \text{BV}_{\text{DSS}} / \Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to $25^{\circ}C$	-	0.67	_	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V	-	-	1	μΑ
		$V_{DS} = 520 \text{ V}, \text{ T}_{C} = 125^{\circ}\text{C}$	-	0.77	-	
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 30$ V, $V_{DS} = 0$ V	-	-	±100	nA
ON CHARACTE	RISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 0.29 \text{ mA}$	2.5	-	4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 6 A	-	210	250	mΩ
9 _{FS}	Forward Transconductance	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 6 \text{ A}$	-	7.4	-	S
DYNAMIC CHA	RACTERISTICS	·	-		•	
C _{iss}	Input Capacitance	$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	-	1010	-	pF
C _{oss}	Output Capacitance		_	25	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	248	-	pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	33	-	pF
Q _{g(tot)}	Total Gate Charge at 10 V	$V_{DS} = 400 \text{ V}, \text{ I}_{D} = 6 \text{ A}, \text{ V}_{GS} = 10 \text{ V}$ (Note 4)	-	24	-	nC
Q _{gs}	Gate to Source Gate Charge		-	6.1	-	nC
Q _{gd}	Gate to Drain "Miller" Charge		-	9.7	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	1.1	-	Ω
WITCHING CH	IARACTERISTICS	·	-		•	
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 6 \text{ A}, \text{ V}_{GS} = 10 \text{ V},$	-	15	-	ns
t _r	Turn-On Rise Time	R _g = 4.7 Ω (Note 4)	_	13	-	ns
t _{d(off)}	Turn-Off Delay Time		-	40	-	ns
t _f	Turn-Off Fall Time		-	7.2	-	ns
SOURCE-DRAII	N DIODE CHARACTERISTICS	•		•		
۱ _S	Maximum Continuous Source to Drain Diode Forward Current		-	-	12	Α
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current		-	-	30	Α
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_{SD} = 6 A$	-	-	1.2	V
t _{rr}	Reverse Recovery Time	V _{DD} = 400 V, I _{SD} = 6 A,	-	251	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 \text{ A}/\mu \text{s}$		3.4	_	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Essentially independent of operating temperature typical characteristics.

TYPICAL PERFORMANCE CHARACTERISTICS

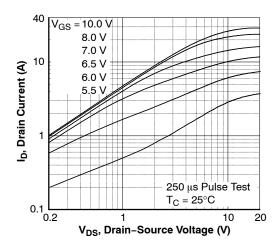
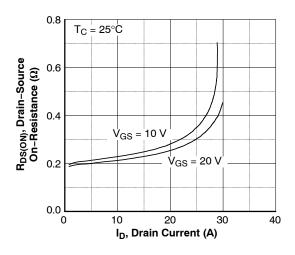
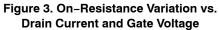


Figure 1. On-Region Characteristics





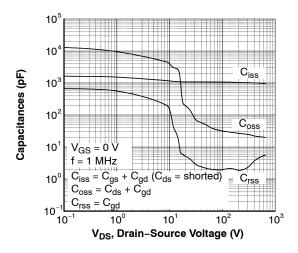


Figure 5. Capacitance Characteristics

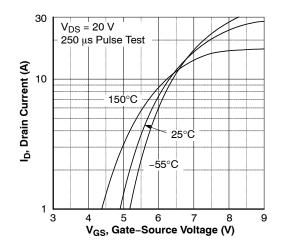
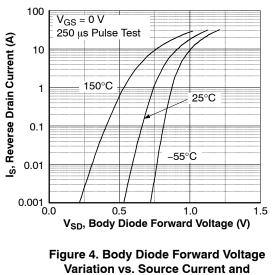


Figure 2. Transfer Characteristics



Temperature

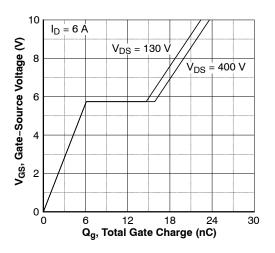
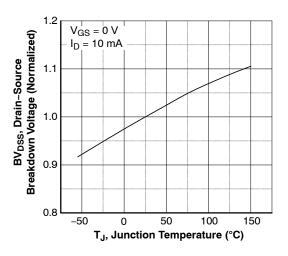
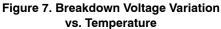


Figure 6. Gate Charge Characteristics

TYPICAL PERFORMANCE CHARACTERISTICS (continued)





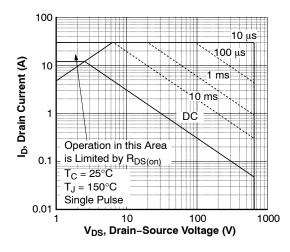


Figure 9. Maximum Safe Operating Area

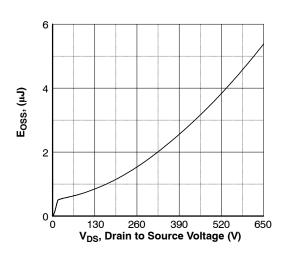


Figure 11. E_{OSS} vs. Drain to Source Voltage

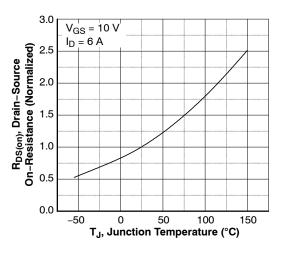


Figure 8. On–Resistance Variation vs. Temperature

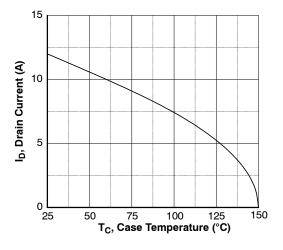


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

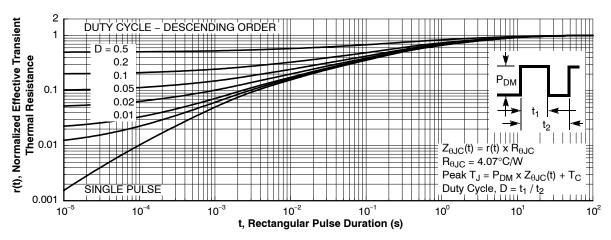
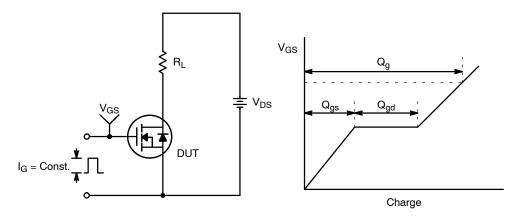


Figure 12. Transient Thermal Response Curve





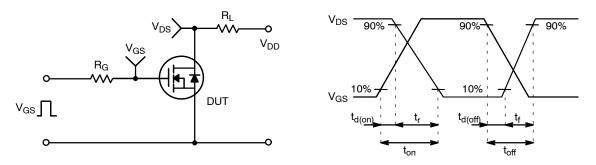
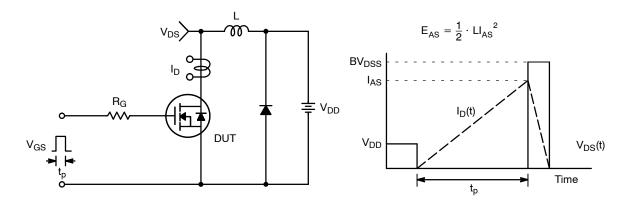


Figure 14. Resistive Switching Test Circuit & Waveforms





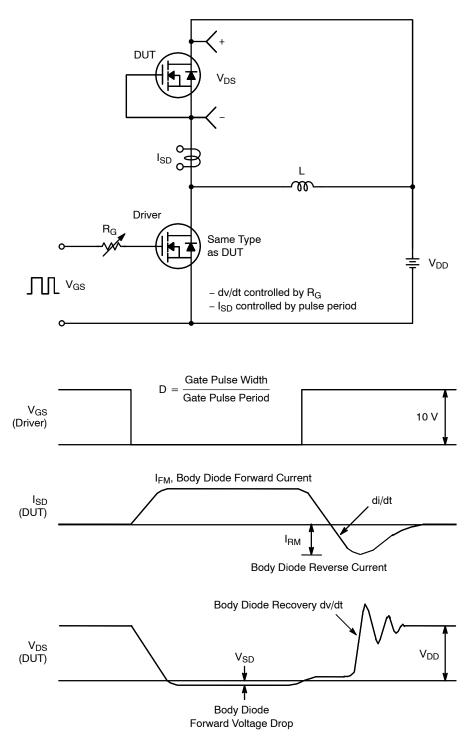
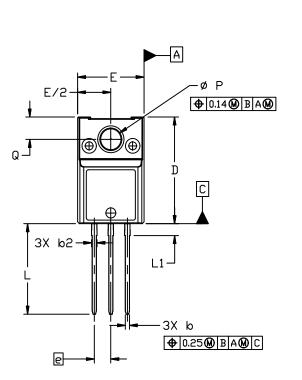


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

SUPERFET is a registered trademark of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries.

PACKAGE DIMENSIONS

TO-220 FULLPACK, 3-LEAD CASE 221BN ISSUE O



NDTES

Α

H1

D1

C

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS

В

A1

A2

SEATING

NOTE 3

- 3. CONTOUR UNCONTROLLED IN THIS AREA.
- DIMENSIONS EXCLUDE BURRS, MOLD FLASH, AND TIE BAR PROTRUSIONS.

	MILLIMETERS			
DIM	MIN.	NDM.	MAX.	
Α	4.60	4.70	4.80	
A1	2.50	2.60	2.70	
A2	2.47	2.57	2.67	
b	0.56	0.63	0.69	
b2			0.90	
с	0.46	0.53	0.59	
D	15.80	16.00	16.20	
D1	9.58	9.68	9.78	
Е	10.00	10.20	10.40	
e		2.54 BSC		
H1	6.32 REF			
L	13.45	13.60	13.75	
L1	1.70	1.80	1.90	
Ρ	3.00	3.10	3.20	
Q	3.25	3.35	3.45	

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <u>www.onsemi.com/site/pdf/Patent-Marking.pdf</u>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor has against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or dea

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

TECHNICAL SUPPORT

ON Semiconductor Website: www.onsemi.com

Email Requests to: orderlit@onsemi.com

North American Technical Support: Voice Mail: 1 800–282–9855 Toll Free USA/Canada Phone: 011 421 33 790 2910 Europe, Middle East and Africa Technical Support: Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative